S₂ [



Dual N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)		
40	0.010 at V _{GS} = 10 V	12	5.9 nC		
40	0.015 at V _{GS} = 4.5 V	10	5.9110		

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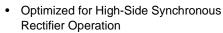
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SO-8

Top View

FEATURES

- · Halogen-free
- TrenchFET® Power MOSFET

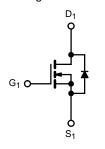


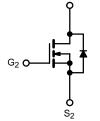


• 100 % UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch





N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	S T _A = 25 °C, unles	s otherwise no	oted		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	40	V		
Gate-Source Voltage	V_{GS}	± 20	7 v		
	T _C = 25 °C		12		
Continuous Proin Current (T. – 150 °C)	T _C = 70 °C		10	1	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	l _D	10 ^{b, c}	1	
	T _A = 70 °C		8 ^{b, c}	1	
Pulsed Drain Current	I _{DM}	45	A		
Continuous Course Desir Diede Current	T _C = 25 °C		3.2	1	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	1.6 ^{b, c}	1	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	17	1	
Avalanche Energy	L = 0.1 IIII	E _{AS}	21	mJ	
	T _C = 25 °C		4.1		
Manierum Davier Disaination	T _C = 70 °C	В	2.5	Ī ,,,	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.1 ^{b, c}	W	
	T _A = 70 °C		1.2 ^{b, c}	1	
Operating Junction and Storage Temperature Ra	T _J , T _{stq}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	39	53	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	25	29	C/VV	

Notes:

- a. Base on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



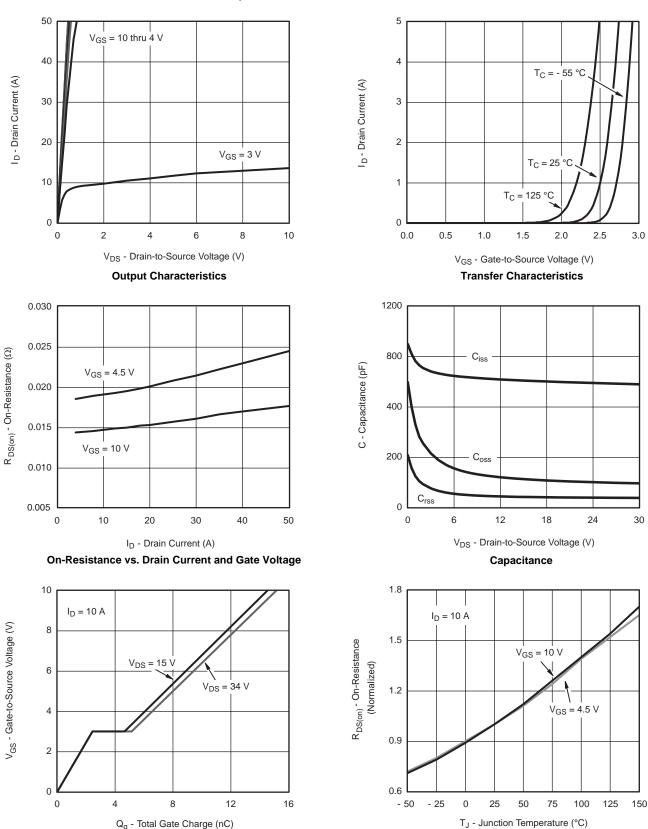
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	1						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		28		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		V _{DS} = 40 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
	_	V _{GS} = 10 V, I _D = 10 A	0.010			_	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A		0.015		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		52		S	
Dynamic ^b							
Input Capacitance	C _{iss}			641			
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		175		pF	
Reverse Transfer Capacitance	C _{rss}			73			
		Vpc = 15 V, Vcc = 10 V, Ip = 10 A		15	23		
Total Gate Charge	Q_g	50 00 5		5.9	10.2		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5		nC	
Gate-Drain Charge	Q _{gd}			2.3		1	
Gate Resistance	R _g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	24	1	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.4 \Omega$		12	18	1	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	24	1	
Fall Time	t _f			10	20	1	
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.4 \Omega$		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	24		
Fall Time	t _f			8	15	1	
Drain-Source Body Diode Characterist	tics			I	L		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			17	۸	
Pulse Diode Forward Current ^a	I _{SM}				45	A	
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L_ = 0 A dl/dt = 100 A/vo T = 25 °C		6	12	nC	
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		8			
Reverse Recovery Rise Time	t _b			7		ns	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



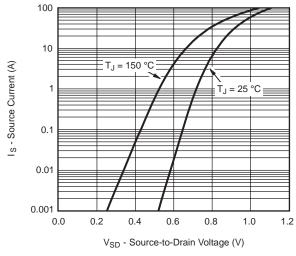


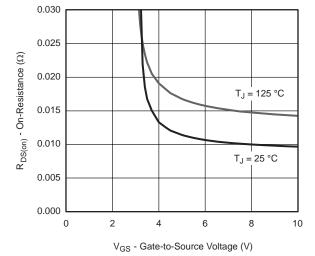
服务热线:400-655-8788

Gate Charge

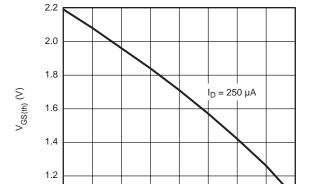
On-Resistance vs. Junction Temperature







Source-Drain Diode Forward Voltage



1.0

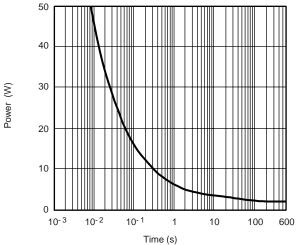
- 50

- 25

0

25

On-Resistance vs. Gate-to-Source Voltage



T_J - Temperature (°C) **Threshold Voltage**

50

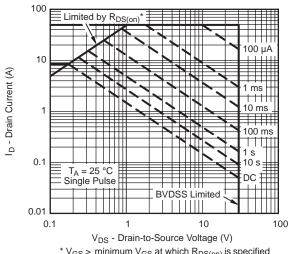
75

100

125

150

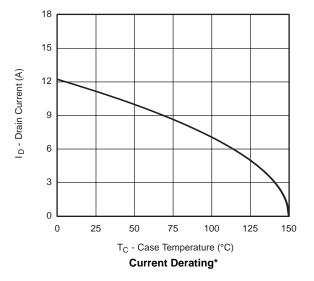
Single Pulse Power, Junction-to-Ambient

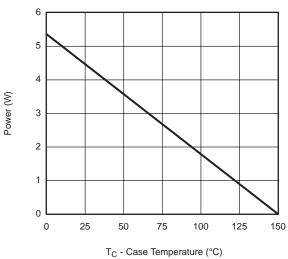


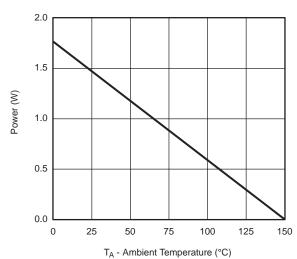
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient







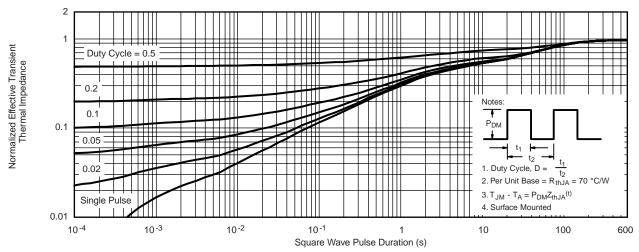


Power Derating, Junction-to-Foot

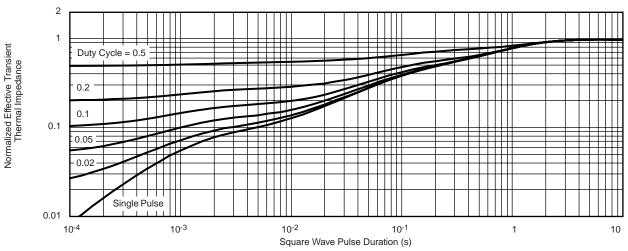
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





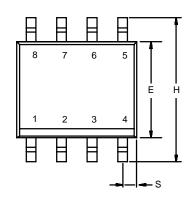
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







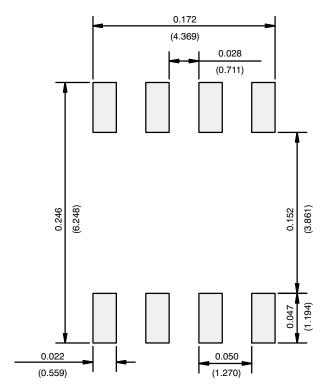
	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pay I 11-San-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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